

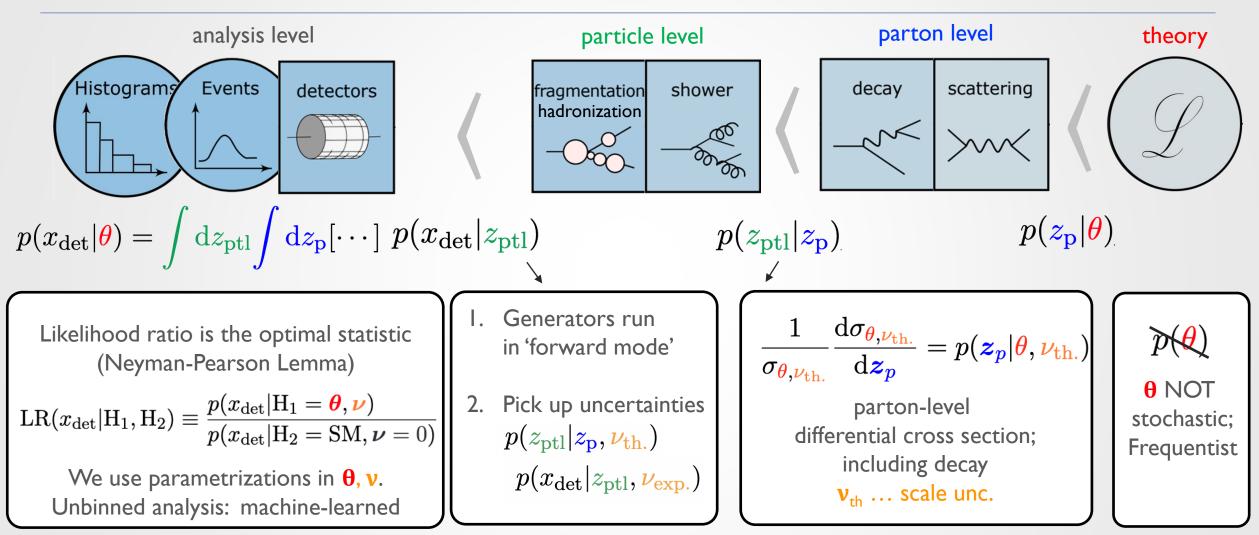
METHODOLOGY FOR SM-EFT SEARCHES IN TTBAR

R. Schöfbeck (HEPHY Vienna, FNAL), Feb 2nd, 2024, TOP workshop



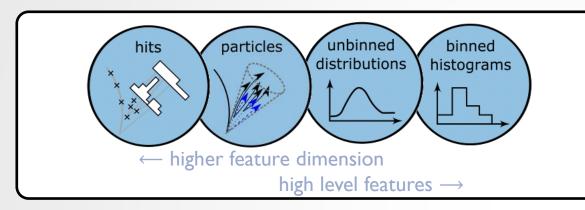
A CONDITIONAL SEQUENCE

adapted from arXiv:2211.01421



QUESTIONS, QUESTIONS, ...

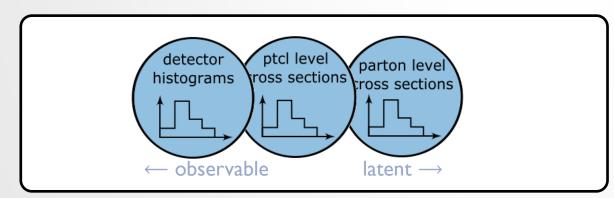
1. How accurately/low-level should the data be represented?



Generic answer: Stop when the level is sufficient for Θ : $p(x_{\text{lower}}|x_{\text{higher}}, \emptyset)$

Particle-level SMEFT [exception]

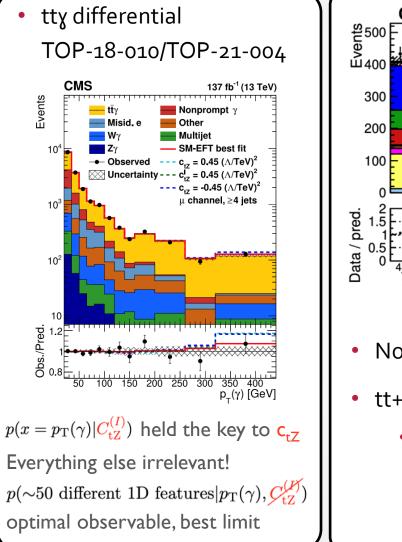
2. Take an intermediate step towards "latent" fiducial regions/gen-level?

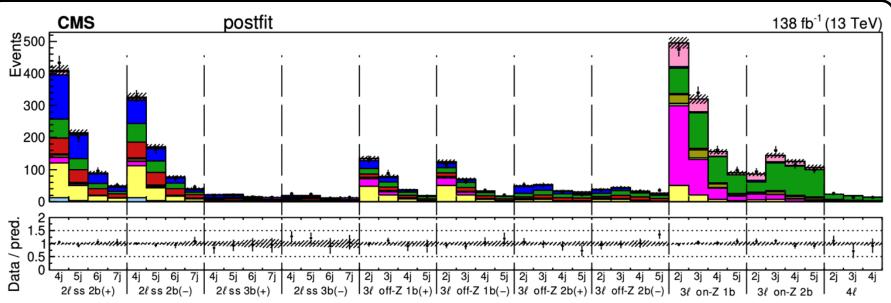


No best answer; make sure systematics modeling allows *combinations*

3. Where to stop, exactly? Publish full likelihood, a Gaussian approximation, CL contours, etc.

DETECTOR LEVEL ANALYSES





- No optimal observable for many Wilson coefficients.
- tt+XTOP-22-006 captures leading SMEFT dependence with $p_T(\ell,j)$ or $p_T(Z)$
 - D=26 dimensional limits using 178 measurements

DETECTOR LEVEL ANALYSES

- Test statistic: Profiled likelihood ratio (unbinned) θ ... SMEFT POI, v_k ... nuisances
- Distribution $q_{\theta}(\mathcal{D}) = -2\log \frac{\max_{\nu} L(\mathcal{D}|\theta, \nu)}{\max_{\nu, \theta} L(\mathcal{D}|\theta, \nu)}$ is asymptotically χ^2 independent of ν
 - Solve $q_{\theta} = F_{\chi^2_{N_{\theta}}}^{-1}(1-\alpha)$ with α =5% for θ to obtain confidence regions.

$$L(\mathcal{D}|\boldsymbol{\theta},\boldsymbol{\nu}) = \operatorname{Pois}_{\mathcal{L}\sigma(\boldsymbol{\theta},\boldsymbol{\nu})}(N) \times \prod_{i=1}^{N} p(\boldsymbol{x}_{i}|\boldsymbol{\theta},\boldsymbol{\nu}) = \operatorname{Pois}_{\mathcal{L}\sigma(\boldsymbol{\theta},\boldsymbol{\nu})}(N) \times \prod_{i=1}^{N} \frac{1}{\sigma_{\boldsymbol{\theta},\boldsymbol{\nu}}} \frac{\mathrm{d}\sigma_{\boldsymbol{\theta},\boldsymbol{\nu}}(\boldsymbol{x}_{i})}{\mathrm{d}\boldsymbol{x}}$$

• Binned approximation for generic detector-level SMEFT analyses

FACTORIZING SMEFT AND SYSTEMATICS

• We approximate the yield in a bin j as

$$\lambda_j(\boldsymbol{\theta}, \boldsymbol{\nu}) \approx \lambda_j(\mathrm{SM}) \cdot (1 + \boldsymbol{\theta}^{\mathsf{T}} \mathbf{R}_{\mathrm{lin}, j} + \boldsymbol{\theta}^{\mathsf{T}} \mathbf{R}_{\mathrm{quad}, j} \boldsymbol{\theta}) \cdot \prod_k \alpha_{j, k}^{\boldsymbol{\nu}_k}$$

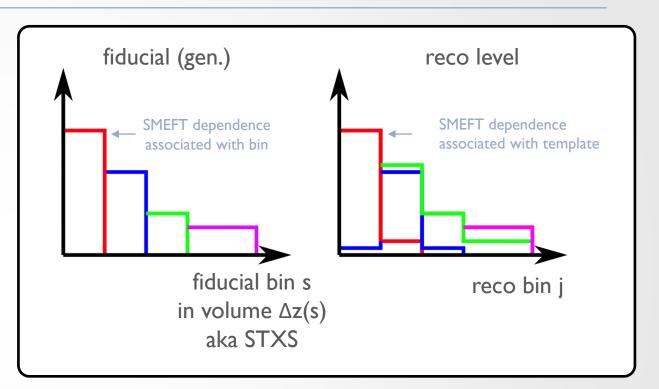
• How to get the SMEFT dependence from simulation? $\lambda_{j}(\boldsymbol{\theta},\boldsymbol{\nu}) = \mathcal{L}(\boldsymbol{\nu}) \int_{\Delta \mathbf{x}(j)} d\mathbf{x} \frac{d\sigma_{\boldsymbol{\theta},\boldsymbol{\nu}}}{d\mathbf{x}} = \mathcal{L}(\boldsymbol{\nu}) \int_{\Delta \mathbf{x}(j)} d\mathbf{x} \int d\mathbf{z} \, \sigma(\boldsymbol{\theta},\boldsymbol{\nu}) p(\mathbf{x},\mathbf{z}|\boldsymbol{\theta},\boldsymbol{\nu})$ $= \mathcal{L}(\boldsymbol{\nu}) \int_{\Delta \mathbf{x}(j)} d\mathbf{x} \int d\mathbf{z} \, \sigma(\boldsymbol{\theta},\boldsymbol{\nu}) p(\mathbf{x},\mathbf{z}|\mathrm{SM},\boldsymbol{\nu}=\mathbf{0}) r(\mathbf{x},\mathbf{z}|\boldsymbol{\theta},\boldsymbol{\nu})$ $= \lambda_{j}(\boldsymbol{\nu}) \int_{\Delta \mathbf{x}(j)} d\mathbf{x} \int d\mathbf{z} \, \sigma(\boldsymbol{\theta},\boldsymbol{\nu}) p(\mathbf{x},\mathbf{z}|\mathrm{SM},\boldsymbol{\nu}=\mathbf{0}) r(\mathbf{x},\mathbf{z}|\boldsymbol{\theta},\boldsymbol{\nu})$ $= \lambda_{j}(\boldsymbol{\nu}) \int_{\Delta \mathbf{x}(j)} d\mathbf{x} \int d\mathbf{z} \, \sigma(\boldsymbol{\theta},\boldsymbol{\nu}) p(\mathbf{x},\mathbf{z}|\mathrm{SM},\boldsymbol{\nu}=\mathbf{0}) r(\mathbf{x},\mathbf{z}|\boldsymbol{\theta},\boldsymbol{\nu})$ $= \lambda_{j}(\boldsymbol{\nu}) \int_{\Delta \mathbf{x}(j)} d\mathbf{x} \int d\mathbf{z} \, \sigma(\boldsymbol{\theta},\boldsymbol{\nu}) p(\mathbf{x},\mathbf{z}|\mathrm{SM},\boldsymbol{\nu}=\mathbf{0}) r(\mathbf{x},\mathbf{z}|\boldsymbol{\theta},\boldsymbol{\nu})$ $= \lambda_{j}(\boldsymbol{\nu}) \int_{\Delta \mathbf{x}(j)} d\mathbf{x} \int d\mathbf{z} \, \sigma(\boldsymbol{\theta},\boldsymbol{\nu}) p(\mathbf{x},\mathbf{z}|\mathrm{SM},\boldsymbol{\nu}=\mathbf{0}) r(\mathbf{x},\mathbf{z}|\boldsymbol{\theta},\boldsymbol{\nu})$ $r = \frac{p(x_{\text{det}}, \cdots, z_{\text{ptl}}, \cdots, z_{\text{p}}|\boldsymbol{\theta})}{p(x_{\text{det}}, \cdots, z_{\text{ptl}}, \cdots, z_{\text{p}}|\text{SM})} = \frac{p(x_{\text{det}}|z_{\text{ptl}}) \cdots p(z_{\text{ptl}}|z_{\text{p}}) \cdots p(z_{\text{p}}|\boldsymbol{\theta})}{p(x_{\text{det}}|z_{\text{ptl}}) \cdots p(z_{\text{ptl}}|z_{\text{p}}) \cdots p(z_{\text{p}}|\text{SM})} = \frac{p(z_{\text{p}}|\boldsymbol{\theta})}{p(z_{\text{p}}|\text{SM})} \sim \frac{|\mathcal{M}(z_{\text{p}}, \boldsymbol{\theta})|^2}{|\mathcal{M}(z_{\text{p}}, \text{SM})|^2}$ Change in likelihood of simulated observation x staged simulation in forward mode: re-calcuable latent-space with latent "history" z going from "SM" to θ Intractable factors cancel theory prediction re-weighted simulation possible "post mortem" assume systematics to factor out - SMEFT is at a higher energy scale than modelling / detector (in CMS EFT combination)

UNFOLDED MEASUREMENTS

- A detector level analysis *fully integrates the latent space* in each bin.
- Unfolding: Also split in fiducial (gen-level) bins

$$\int_{\Delta \boldsymbol{x}(j)} \mathrm{d}\boldsymbol{x} \int \mathrm{d}\mathbf{z} \to \int_{\Delta \boldsymbol{x}(j)} \mathrm{d}\boldsymbol{x} \sum_{f} \int_{\Delta \mathbf{z}(f)} \mathrm{d}\mathbf{z} \to \sum_{f} R_{f}(\boldsymbol{\theta}) \lambda_{j,f}$$

- SMEFT dependence on the fiducial bin
- A good approximation if p(x|z) is well localized and independent of θ.
- Otherwise, SMEFT "acceptance" effects.
 - TTbar amenable to unfolding
 - Even STXS acceptance effects are under control
- Well defined data representation for the outside.



unfolded: SMEFT effects on the fiducial bin $L(\mathcal{D}|\boldsymbol{\theta}, \boldsymbol{\nu}) = \prod_{j=1}^{N_{\text{bins}}} \operatorname{Pois} \left(n_j \Big| \sum_f \lambda_{j,f}(\boldsymbol{\nu}) R_f(\boldsymbol{\theta}) + b_j(\boldsymbol{\nu}) \right) \prod_{k=1}^{N_{\text{nuis.}}} C_k(\boldsymbol{\nu}_k)$

χ^2 APPROXIMATION + CMS EFT COMBINATION

- All cases enter in the CMS EFT combination
 - $\rightarrow\,$ Higgs:
 - <u>CMS-HIG-19-015</u>, STXS H $\rightarrow \gamma\gamma$
 - \rightarrow Top:
 - <u>CMS-TOP-17-023</u>, single top, t-channel
 - <u>CMS-TOP-17-002</u>, $t\bar{t}$
 - $\underline{\text{CMS-TOP-22-006}}, t\bar{t}+X, t+X$
 - $\rightarrow\,$ Electroweak:
 - <u>CMS-SMP-20-005</u>, W γ
 - <u>CMS-SMP-18-004</u>, WW
 - <u>CMS-SMP-18-003</u>, $Z \rightarrow \nu \bar{\nu}$
 - hep-ex/0509008, EWPO from LEP+SLC
 - \rightarrow QCD:
 - <u>CMS-SMP-20-011</u>, inclusive jets
- Highlight #1: PCA
- Highlight #2: "post mortem reweighting"
 - Evaluate $\frac{|\mathcal{M}(z_{\mathrm{p}}, \theta)|^2}{|\mathcal{M}(z_{\mathrm{p}}, \mathrm{SM})|^2}$ on existing sample!!

Gaussian approximate the likelihood ratio using the total covariance of the unfolded measurement

$$\chi^{2}(\boldsymbol{\theta}) = \frac{\exp\left\{-\frac{1}{2}\left((\hat{\boldsymbol{R}} - \boldsymbol{R}(\boldsymbol{\theta}))V^{-1}(\hat{\boldsymbol{R}} - \boldsymbol{R}(\boldsymbol{\theta}))\right)\right\}}{(2\pi)^{M/2}\det(V)}$$

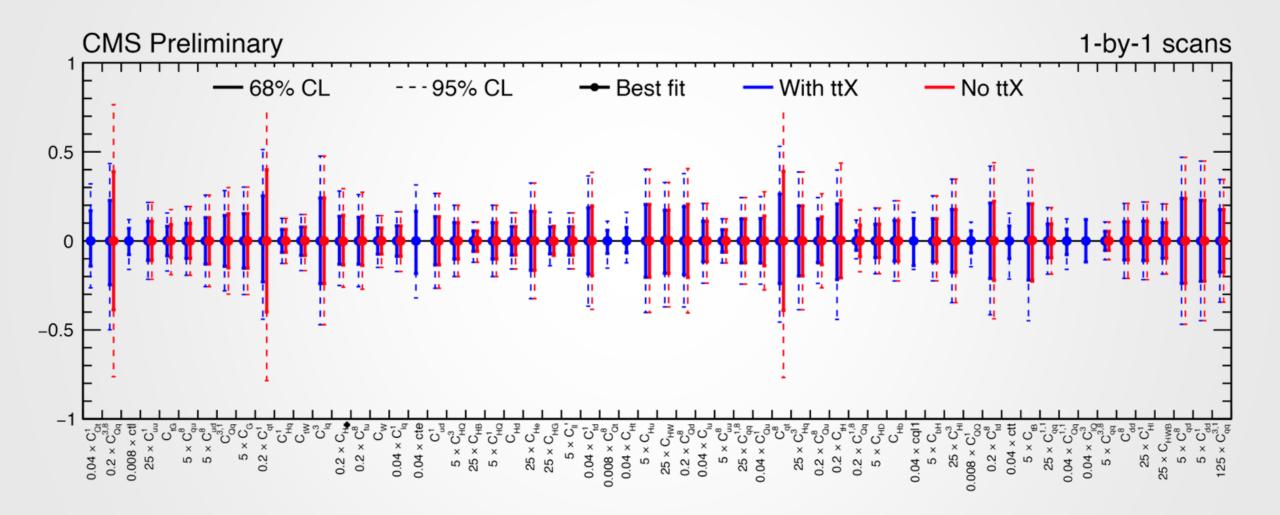
unfolded: SMEFT effects on the fiducial bin

$$L(\mathcal{D}|\boldsymbol{\theta},\boldsymbol{\nu}) = \prod_{j=1}^{N_{\text{bins}}} \operatorname{Pois}\left(n_j \Big| \sum_f \lambda_{j,f}(\boldsymbol{\nu}) R_f(\boldsymbol{\theta}) + b_j(\boldsymbol{\nu}) \right) \prod_{k=1}^{N_{\text{nuis.}}} C_k(\nu_k)$$

SMEFT effects on the detector-level bin

$$L(\mathcal{D}|oldsymbol{ heta},oldsymbol{
u}) = \prod_{j=1}^{N_{ ext{bins}}} ext{Pois}\left(n_j \Big| R_j(oldsymbol{ heta}) \lambda_j(oldsymbol{
u}) + b_j(oldsymbol{
u})
ight) \prod_{k=1}^{N_{ ext{nuis.}}} C_k(
u_k)$$

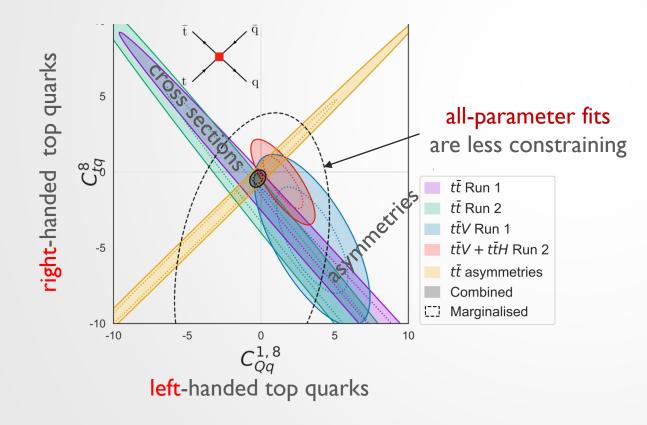
CMS EFT COMBINATION



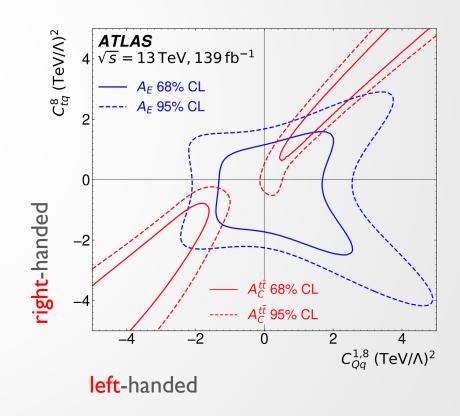
EXTERNAL GLOBAL FITS

[Ellis, Sanz, et.al. [FitMaker JHEP04(2021)279]

- Early example: Left- and right-handed 4-fermion operators
 - two-at-atime: tight constraint from combined measurement
 - Factor ~10 less powerful marginalized



ATLAS charge asymmetry
 vs. energy asymmetry (two-at-a-time)
 shows comparable same pattern



ML4EFT R. Ambrosio, J. Hoeve, M. Madigan, J. Rojo, V. Sanz [2211.02058]

IMPROVING HIGH DIMENSIONAL LIMITS

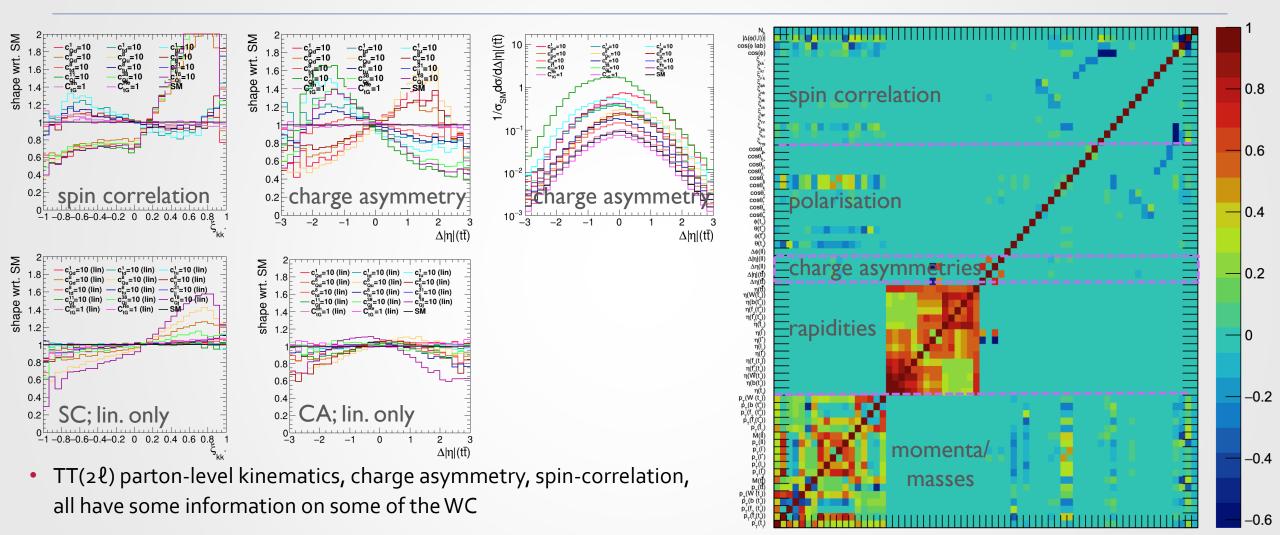


- Binned $(p_T^{\ell\bar{\ell}}, \eta_\ell)$ C, Unbinned ML $(p_T^{\ell \bar{\ell}}, \eta_\ell)$ $c_{qt}^{(8)}$ Unbinned ML (18 features) SM • 0.0 $c_{Qu}^{(8)}$ -0.50.25 $\mathcal{C}_{Qq}^{(3,8)}$ (+) + 0.00 + -0.250.25+ 0.00(+) $\mathcal{C}_{Qq}^{(1,8)}$ -0.25 $c_{tu}^{(8)}$ $c_{at}^{(8)}$ $c_{O}^{(8)}$ -0.50
 - [ML4EFT] study ZH and top quark pairs

 $c^{(3,8)}_{2}$

- Pheno study with parametrized NN classifiers
- Top quark pairs in low ($N_f=2$) and high feature dimension $N_f=18$
 - Pairs of 2D limits with 6 more ops marginalized
 - Binned vs. unbinned: Some gain w/ unbinned when using 2 features
 - High dimensional observation (N_f=18) constraining a high-dimensional (N_{coef}=8) model using an SM candle
 - Large improvement for N_f=18– mostly in (only) the marginalized limits
 - Whether the sensitivity gain survives systematics in an unbinned detector-level analysis is an open question

SMEFT EFFECTS & FEATURE CORRELATION



16 operators, 72 features: TTbar is a SM candle with EFT sensitivity:
 Ideal case to develop methodology for an unbinned analyses

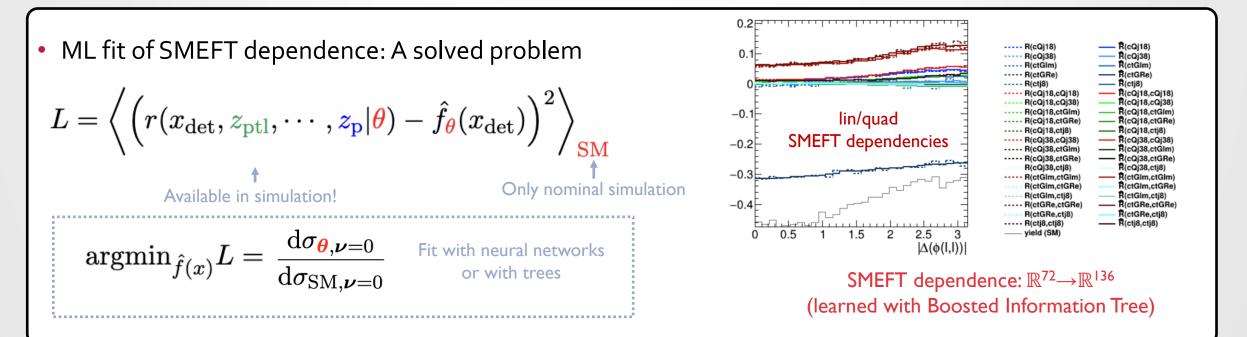
linear feature correlation in $tt(2\ell)$ for $H_T > 500$

TOWARDS AN UNBINNED ANALYSIS

• We must be able to efficiently evaluate

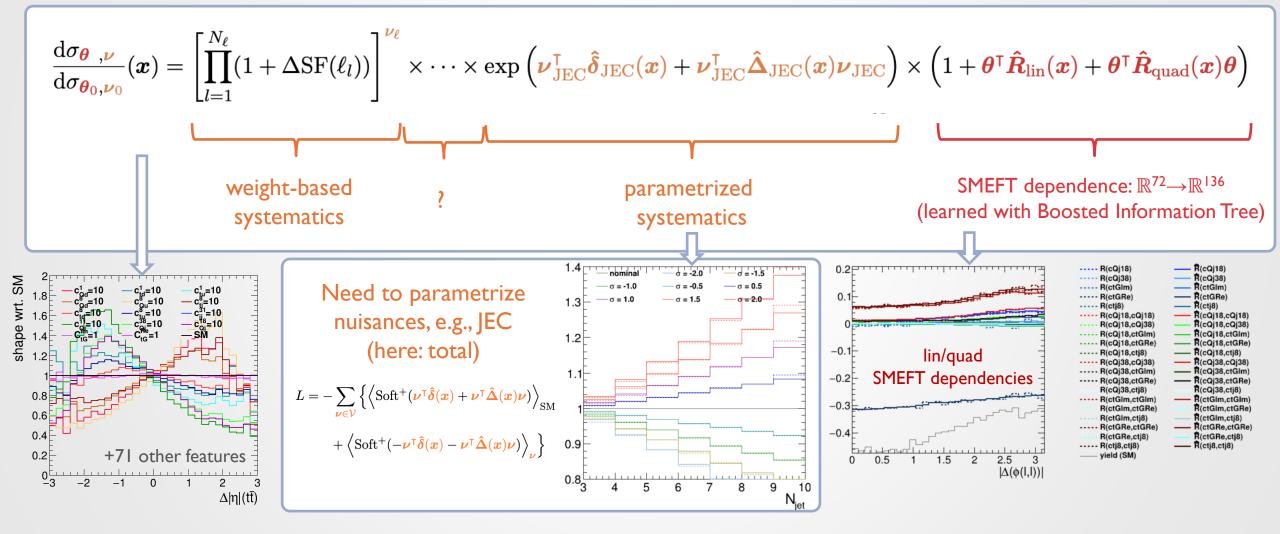
$$q_{\boldsymbol{\theta},\boldsymbol{\nu}}(\mathcal{D}) \equiv \log \frac{L(\mathcal{D}|\boldsymbol{\theta},\boldsymbol{\nu})}{L(\mathcal{D}|\boldsymbol{\theta}_{0},\boldsymbol{\nu}_{0})} = -\mathcal{L}(\boldsymbol{\nu})\sigma(\boldsymbol{\theta},\boldsymbol{\nu}) + \mathcal{L}(\boldsymbol{\nu}_{0})\sigma(\boldsymbol{\theta}_{0},\boldsymbol{\nu}_{0}) + \sum_{i=1}^{N(\mathcal{D})} \log \left(\frac{\mathcal{L}(\boldsymbol{\nu})}{\mathcal{L}(\boldsymbol{\nu}_{0})} \frac{\mathrm{d}\sigma_{\boldsymbol{\theta}}}{\mathrm{d}\sigma_{\boldsymbol{\theta}_{0},\boldsymbol{\nu}_{0}}}(\boldsymbol{x}_{i})\right) + \sum_{k=1}^{N_{nuis.}} \log \frac{C_{k}(\boldsymbol{\nu}_{k})}{C_{k}(\boldsymbol{\nu}_{0,k})}$$

• Parametrize the differential cross section ratio in terms of POIs and nuisances.



PARAMETRIZING THE LIKELIHOOD RATIO

What about the systematic dependence?



BESTIARY OF SYSTEMATICS (RECIPIES)

Autalops Die Antilope



ince minufaherfahen Duraillongen der Anthepe sind in Bestiarien und Entyklopidien ro finden. Auferdom sind einige wenige Antilopen auf den Scitoseinders von Handscheiten abgehöhlt. Des beschreihungen zuführe besten die Antilope Härner in Form einer rikkoren, dass der Trafel sich seiner bemächtigt. In anderen Sige, mit der sie Biume fallen kann. Auch habe sie die Ange-Fassungen werden die Hierner, die ihrem Besitzer bei unachtnodudurit, diren Durer an den Ullern des Euglerar zu kinchen. samens Gebrauch zum Nachteil gewichen kännen, zum Bäld no cin Struch namens Hiraciae wichst, deven Zweige lang. Für Venuchungen: William und Ehebruch, Verleumdung dists und greunder eind. Wens die Antilope doors Strauk- und Vergnigungsucht, eder auch - wie im moralisierenden not siche, kann sie nicht widertehen, darin zu spielen, und Bostarium von Perrs de Beausis - Wein und France. verhoddert sich unweigerlich mit ihren Hörnern in den Zurigen, Bustrationen, die rom Hyuidges impiriert sind, jedach ist sie nach achwieriger zu fassen als das Tächten, dem ernen derieftehen "mordnierenden" Boniarium, deuen denn im Gegenute zu diesem läut sie sich nicht mithöle prinhische Urweisen Finle des 2. oder Anlang die 3. Die, in view Jungfrau einfangen, wendern man mass abwarten, bie Mexandria remand, reigen die Tier, wie es, rinnel pfungen, sie ich in den Zweigen eines Strauchs verfangt (Uds. 5, 364). kämpft und Scherie zusmißt, was ihm jedoch nur weinter Nach dem Prinzip der formalen Analogie warde die Antilope secretars hie Aufmerkamikeit des Japo einstigt.

Sanbidd far den gongefälligen Manschen, der sich um ein 👘 wie der schnelle Varbeiner, war ihm übeliche morabianende regendhaften Leben homüle. Die beiden Ellenor stehen für

das Alte und Neue Testament, darch die der Christ Laner son Kleper und Sode abtannen kann, us wie die Anthope Bäume koppe, die die den Weg versperren. Doch dief sich der Christ nicht in dess Latter vererichen, will et nicht Last Arnaud Zocket ihndt die Antilope dem Einhorn,

mit dem Sigemenner verglahen, einem imaginäten Tiet, Monifolevende Beelarien interpreteren die Antilope als das zu seiner Veneißigung deselbe Waffe zur Verfügung hat Werrungen einbeschre,

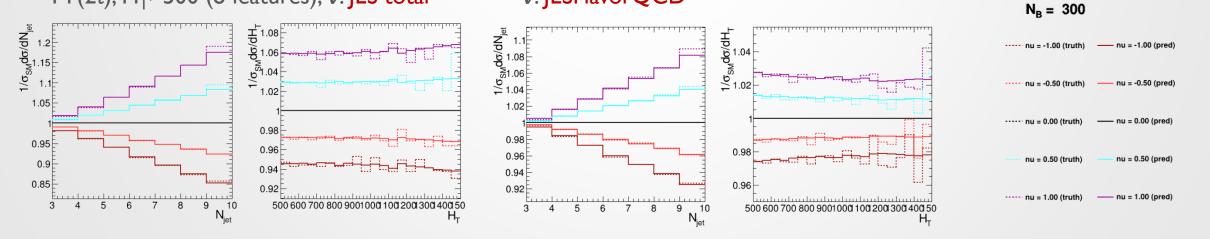






CALIBRATION SYSTEMATICS

Need: Likelihood ratio for the same observatio **x** and different **v**: $r(\mathbf{x}|\boldsymbol{\nu}, \mathbf{0}) = \frac{p(\mathbf{x}|\boldsymbol{\nu})}{p(\mathbf{x}|\mathbf{0})}$ Have: JME prescription "J" that varies **x** and **v** such that the likleihood const.: $p(\mathbf{x}_i, \mathbf{z}_i | \mathbf{0}) = p(J_{\nu}(\mathbf{x}_i, \mathbf{z}_i), \mathbf{z}_i | \boldsymbol{\nu})$ $\frac{p(\boldsymbol{x}|\boldsymbol{\nu})}{p(\boldsymbol{x}|\boldsymbol{0})} = \exp\left(\boldsymbol{\nu}_{\text{JEC}}^{\mathsf{T}} \hat{\boldsymbol{\delta}}_{\text{JEC}}(\boldsymbol{x}) + \boldsymbol{\nu}_{\text{JEC}}^{\mathsf{T}} \hat{\boldsymbol{\Delta}}_{\text{JEC}}(\boldsymbol{x}) \boldsymbol{\nu}_{\text{JEC}}\right)$ Solution: Train a parametric regressor a parametrisation $L = -\sum_{\mathbf{x}} \left\{ \left\langle \operatorname{Soft}^+(\boldsymbol{\nu}^{\mathsf{T}} \hat{\boldsymbol{\delta}}(\boldsymbol{x}) + \boldsymbol{\nu}^{\mathsf{T}} \hat{\boldsymbol{\Delta}}(\boldsymbol{x}) \boldsymbol{\nu} \right) \right\rangle_{\mathrm{SM}} + \left\langle \operatorname{Soft}^+(-\boldsymbol{\nu}^{\mathsf{T}} \hat{\boldsymbol{\delta}}(\boldsymbol{x}) - \boldsymbol{\nu}^{\mathsf{T}} \hat{\boldsymbol{\Delta}}(\boldsymbol{x}) \boldsymbol{\nu} \right) \right\rangle_{\boldsymbol{\nu}} \right\}$ a factor in the LLR parametric in v_{IFC} JEC variied samples Tree or NN Tree or NN Use many! $TT(2\ell)$, $H_T > 500$ (8 features), v: [ES total] v: [ESFlavorQCD



OBJECT LEVEL: B-TAGGING

• Must we learn b-tagging? After all, it produces event weights that can be interpreted as likleihood ratio

$$F(\nu_k, \text{jets}) = \prod_{\text{tagged jets}} \varepsilon_f(p_{\text{T}}, \eta) \left(\text{SF}_f(p_{\text{T}}, \eta) + \nu_k \Delta \text{SF}_{f,k}(p_{\text{T}}, \eta) \right)$$

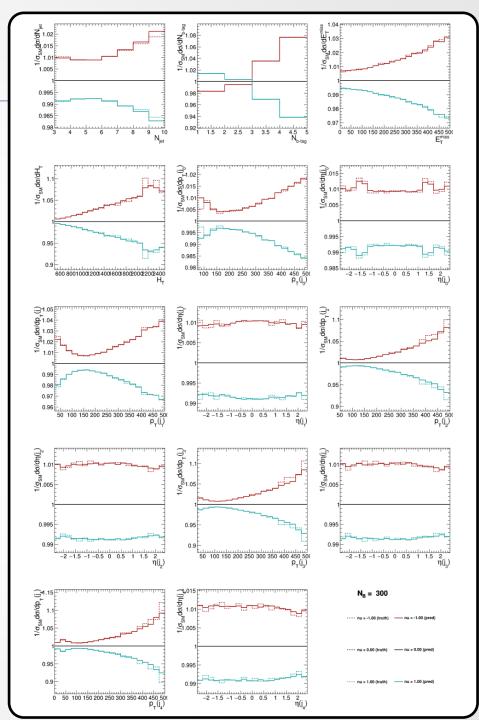
$$\times \prod_{\text{untagged jets}} (1 - \varepsilon_f(p_{\mathrm{T}}, \eta) (\mathrm{SF}_f(p_{\mathrm{T}}, \eta) + \nu_k \Delta \mathrm{SF}_{f,k}(p_{\mathrm{T}}, \eta)))$$

$$\omega_{\boldsymbol{
u},i} = \omega_i \prod_{k=1}^K rac{F(\boldsymbol{
u}_k, ext{jets in event } i)}{F(0, ext{jets in event } i)}.$$

• However f, the true jet flavor, is latent. Jet p_T , η are observed.

$$\frac{\omega_{\boldsymbol{\nu},i}}{\omega_i} \approx \frac{p(\mathbf{x}_i, \mathbf{z}_i | \boldsymbol{\nu})}{p(\mathbf{x}_i, \mathbf{z}_i | \mathbf{0})} = r(\mathbf{x}_i, \mathbf{z}_i | \boldsymbol{\nu}, \mathbf{0}) \qquad \begin{array}{l} \text{B-tag reweighting} \\ \text{is latent} \end{array}$$

- Can not compute the LLR(v_{HF}) test statistic from an observation
- B-tagging must be learned.
- Pro: Covers efficiency & udsg/c-fakes



LEPTON UNCERTAINTIES & NORMALIZATIONS

• Must we learn lepton-efficiency SF?

$$\omega_{\nu,i} = \omega_i \prod_{k=1}^{K} \prod_{\ell=1}^{N_{\ell}(i)} \left(1 + \nu_k \frac{\Delta_k \text{SF}(\ell)}{\text{SF}(\ell)} \right)$$

- Parametrized in terms of measured quantities.
 Need not be learned.
- Normalization uncertainties
 - There is a catch: non-prompt/fakes are sourced by jets, hence we do not use scale factors.
- The non-prompt background component is on the same footing as tW, diboson, ttV backgrounds
- Train a multiclassifier to scale the cross sections within uncertainties

SUMMARY

LEARNING SYSTEMATICS

Let's start with Cross-Entropy and a single variation v

$$L = -\int \mathrm{d}\boldsymbol{x} \left\{ p(\boldsymbol{x}|\mathrm{SM}) \log \hat{f}_{\boldsymbol{\nu}}(\boldsymbol{x}) + p(\boldsymbol{x}|\boldsymbol{\nu}) \log(1 - \hat{f}_{\boldsymbol{\nu}}(\boldsymbol{x})) \right\}$$

- L converges to f^{*}_ν(x) ~ 1/(1 + p(x|ν)/p(x|SM))
 To learn a more general dependence, let's inject our exponential ansatz for NN outputs δ, Δ

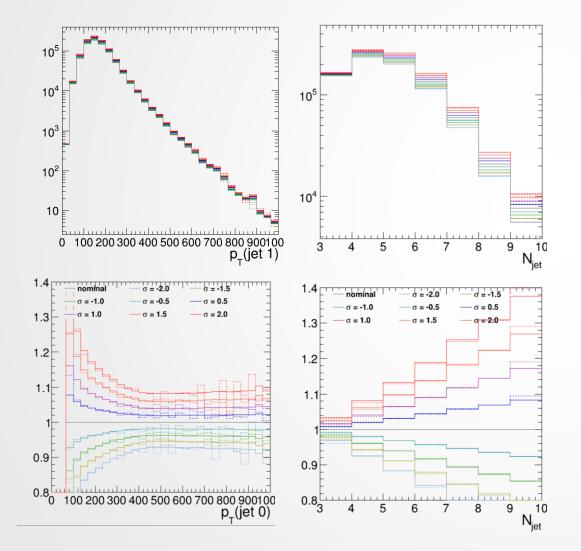
$$\hat{f}_{\boldsymbol{\nu}}(\boldsymbol{x}) = \frac{1}{1 + \exp\left(\boldsymbol{\nu}^{\mathsf{T}}\hat{\delta}(\boldsymbol{x}) + \boldsymbol{\nu}^{\mathsf{T}}\hat{\Delta}(\boldsymbol{x})\boldsymbol{\nu}\right)}$$

• This gives: $L = \sum_{\boldsymbol{\nu}\in\mathcal{V}} \int d\boldsymbol{x} \left\{ \sigma(\mathrm{SM}) \, p(\boldsymbol{x}|\mathrm{SM}) \log\left(1 + \exp\left(\boldsymbol{\nu}^{\mathsf{T}}\hat{\delta}(\boldsymbol{x}) + \boldsymbol{\nu}^{\mathsf{T}}\hat{\Delta}(\boldsymbol{x})\boldsymbol{\nu}\right)\right) + \sigma(\boldsymbol{\nu}) \, p(\boldsymbol{x}|\boldsymbol{\nu}) \log\left(1 + \exp\left(-\boldsymbol{\nu}^{\mathsf{T}}\hat{\delta}(\boldsymbol{x}) - \boldsymbol{\nu}^{\mathsf{T}}\hat{\Delta}(\boldsymbol{x})\boldsymbol{\nu}\right)\right) \right\}$

which we can write as $L = -\sum_{\mathbf{x}} \left\{ \left\langle \operatorname{Soft}^+(\boldsymbol{\nu}^{\mathsf{T}} \hat{\boldsymbol{\delta}}(\boldsymbol{x}) + \boldsymbol{\nu}^{\mathsf{T}} \hat{\boldsymbol{\Delta}}(\boldsymbol{x}) \boldsymbol{\nu} \right) \right\rangle_{\mathrm{SM}} + \left\langle \operatorname{Soft}^+(-\boldsymbol{\nu}^{\mathsf{T}} \hat{\boldsymbol{\delta}}(\boldsymbol{x}) - \boldsymbol{\nu}^{\mathsf{T}} \hat{\boldsymbol{\Delta}}(\boldsymbol{x}) \boldsymbol{\nu} \right) \right\rangle_{\boldsymbol{\nu}} \right\}$

LEARNING JEC & OTHERS

• As a start, fit 7 features to JEC-total [all plots]



Probably more precise than binned 2-point variations

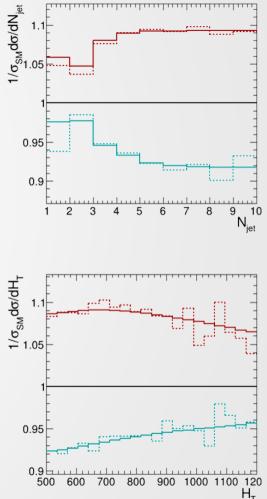
Expect no issues with fitting split JEC nuisance effects

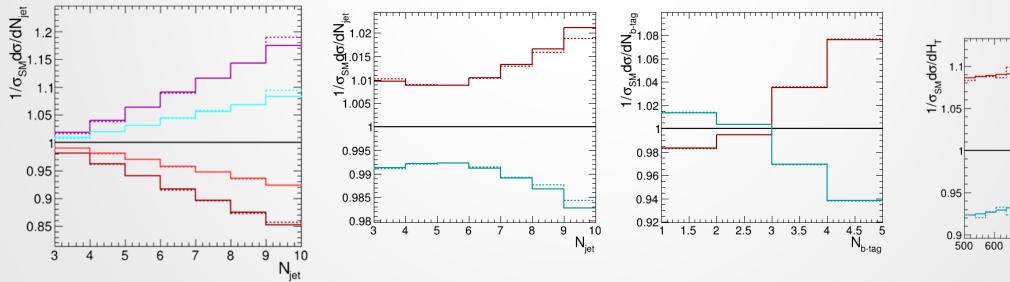
(Famous last words.)

BOOSTED PARAMETRIC TREE

- Long story short: We made a parametric tree-boosting algorithm that learns the Taylor series of the log-likelihood ratio $\exp\left(\nu_{\rm JEC}^{T} \hat{\delta}_{\rm JEC}(x) + \nu_{\rm JEC}^{T} \hat{\Delta}_{\rm JEC}(x)\nu_{\rm JEC}\right)$
- It has the usual interpretation as a Fisher-Information optimum

$$L[\mathcal{J}] = \sum_{j \in \mathcal{J}} \sum_{\boldsymbol{\nu} \in \mathcal{V}} \left[\lambda_{j,\mathbf{0}} \log \left(1 + \frac{\lambda_{j,\boldsymbol{\nu}}}{\lambda_{j,\mathbf{0}}} \right) + \lambda_{j,\boldsymbol{\nu}} \log \left(1 + \frac{\lambda_{j,\mathbf{0}}}{\lambda_{j,\boldsymbol{\nu}}} \right) \right] = -\frac{1}{4} \sum_{j \in \mathcal{J}} \sum_{\boldsymbol{\nu} \in \mathcal{V}} \nu_a \nu_b I_{(ab),j} + \dots$$





TOOLS FOR R&D: UNBINNED ASIMOV DATASET

• [ML4EFT] derives the non-centrality term of the asymptotic χ^2 distribution of the test statistic as

$$-\frac{1}{2}\Lambda(\mathcal{D}) = -\mathcal{L}(\boldsymbol{\nu})\sigma(\boldsymbol{\theta},\boldsymbol{\nu}) + \mathcal{L}(\boldsymbol{\nu}_0)\sigma(\boldsymbol{\theta}_0,\boldsymbol{\nu}_0) + \left\langle \log\left(\frac{\mathcal{L}(\boldsymbol{\nu})}{\mathcal{L}(\boldsymbol{\nu}_0)}\frac{\mathrm{d}\sigma_{\boldsymbol{\theta}}}{\mathrm{d}\sigma_{\boldsymbol{\theta}_0,\boldsymbol{\nu}_0}}(\boldsymbol{x}_i)\right)\right\rangle_{\boldsymbol{\theta}_0,\boldsymbol{\nu}_0} + \sum_{k=1}^{N_{nuis.}}\log\frac{C_k(\boldsymbol{\nu}_k)}{C_k(\boldsymbol{\nu}_{0,k})}$$

• It is quite marvelous that, after minimizing the LLR, we can compute the asymptotic distribution of the test statistic for arbitrary parameter points without toys

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 J. Brehmer, K. Cranmer, G. Louppe, J. Pavez [<u>1805.00013</u>] [<u>1805.00020</u>] [<u>1805.12244</u>]
 J. Brehmer, F. Kling, I. Espejo, K. Cranmer [<u>1907.10621</u>]
 - J. Brehmer, S. Dawson, S. Homiller, F. Kling, T. Plehn
 - A. Butter, T. Plehn, N. Soybelman, J. Brehmer
 - established many of the *main ideas* & *statistical interpretation* in various *NN applications*

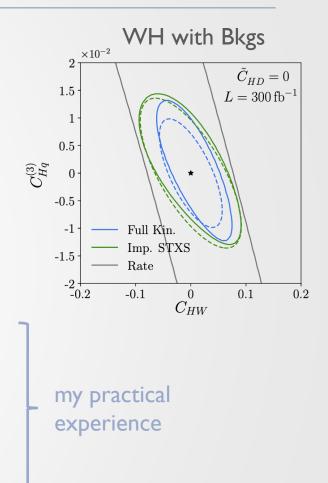
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- Parametrized classifiers for SM-EFT: NN with quadratic structure
 - S. Chen, A. Glioti, G. Panico, A. Wulzer
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 - S. Chatterjee, S. Rohshap, N. Frohner, <u>R.S.</u>, D. Schwarz [<u>2107.10859</u>], [<u>2205.12976</u>]
- ML4EFT R. Ambrosio, J. Hoeve, M. Madigan, J. Rojo, V. Sanz [2211.02058]
- All approaches are "SMEFT-specific ML" with differences mostly on the practical side



$$L = \sum_{\theta \in \mathcal{B}} \left(\langle \hat{f}(x; \theta)^2 \rangle_{\theta} + \langle (1 - \hat{f}(x; \theta))^2 \rangle_{\text{SM}} \right)$$

$$\stackrel{\bullet}{\xrightarrow{\theta - \text{ aware}}} EFT \text{ sample} \qquad SM \text{ sample}$$

We start with SM and BSM samples

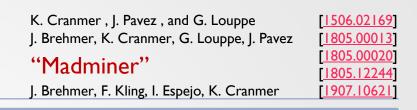
$$= \sum_{\theta \in \mathcal{B}} \int dx \, dz \, \left(p(x, z | \theta) \hat{f}(x; \theta)^2 + p(x, z | SM) (1 - \hat{f}(x; \theta))^2 \right)$$
 Let's write this under one integral
z ... latent space

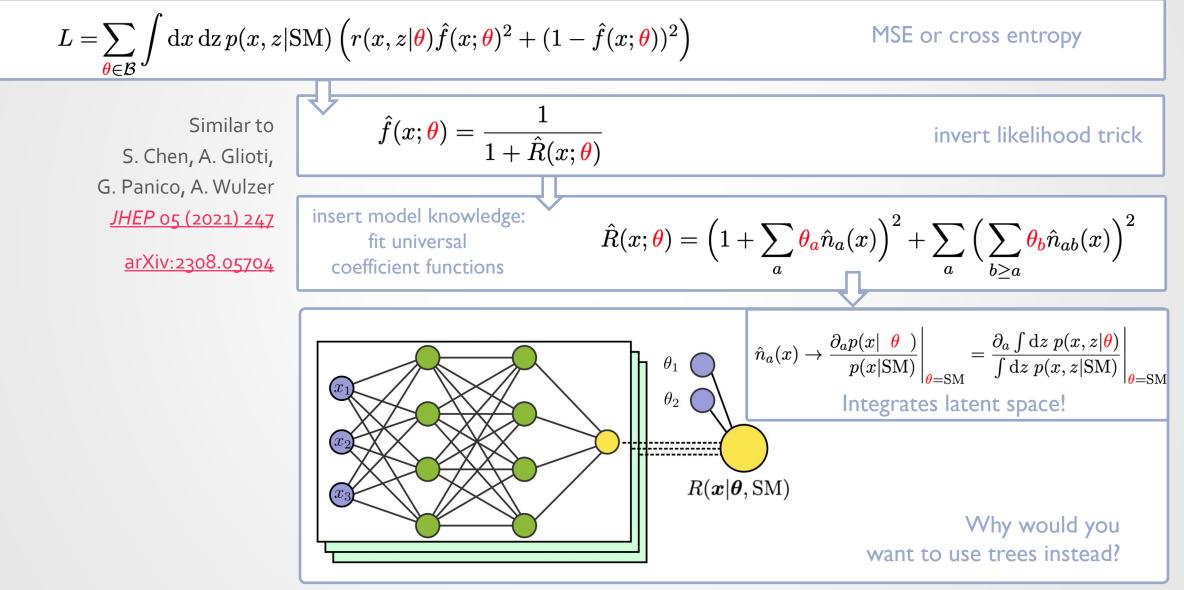
$$r = \frac{p(x_{\text{det}}, \cdots, z_{\text{ptl}}, \cdots, z_{\text{p}}|\boldsymbol{\theta})}{p(x_{\text{det}}, \cdots, z_{\text{ptl}}, \cdots, z_{\text{p}}|\mathbf{SM})} = \frac{p(x_{\text{det}}|z_{\text{ptl}}) \cdots p(z_{\text{ptl}}|z_{\text{p}}) \cdots p(z_{\text{p}}|\boldsymbol{\theta})}{p(x_{\text{det}}|z_{\text{ptl}}) \cdots p(z_{\text{ptl}}|z_{\text{p}}) \cdots p(z_{\text{p}}|\mathbf{SM})} = \frac{p(z_{\text{p}}|\boldsymbol{\theta})}{p(z_{\text{p}}|\mathbf{SM})} \sim \frac{|\mathcal{M}(z_{\text{p}}, \boldsymbol{\theta})|^2}{|\mathcal{M}(z_{\text{p}}, \mathbf{SM})|^2}$$

Change in likelihood of simulated observation x with latent "history" z going from "SM" to θ

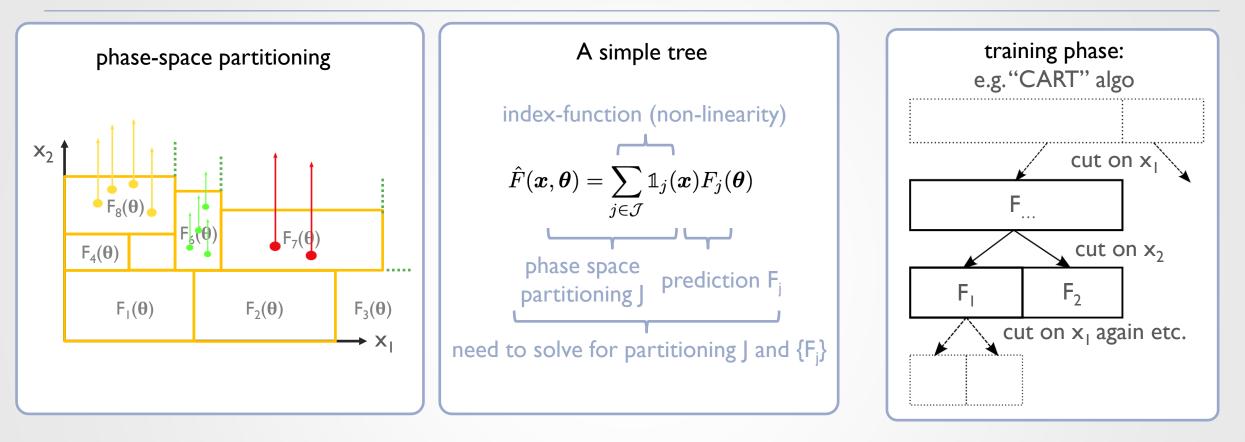
staged simulation in forward mode: Intractable factors cancel re-calcuable theory prediction weighted simulation

PARAMETRIZED CLASSIFIERS



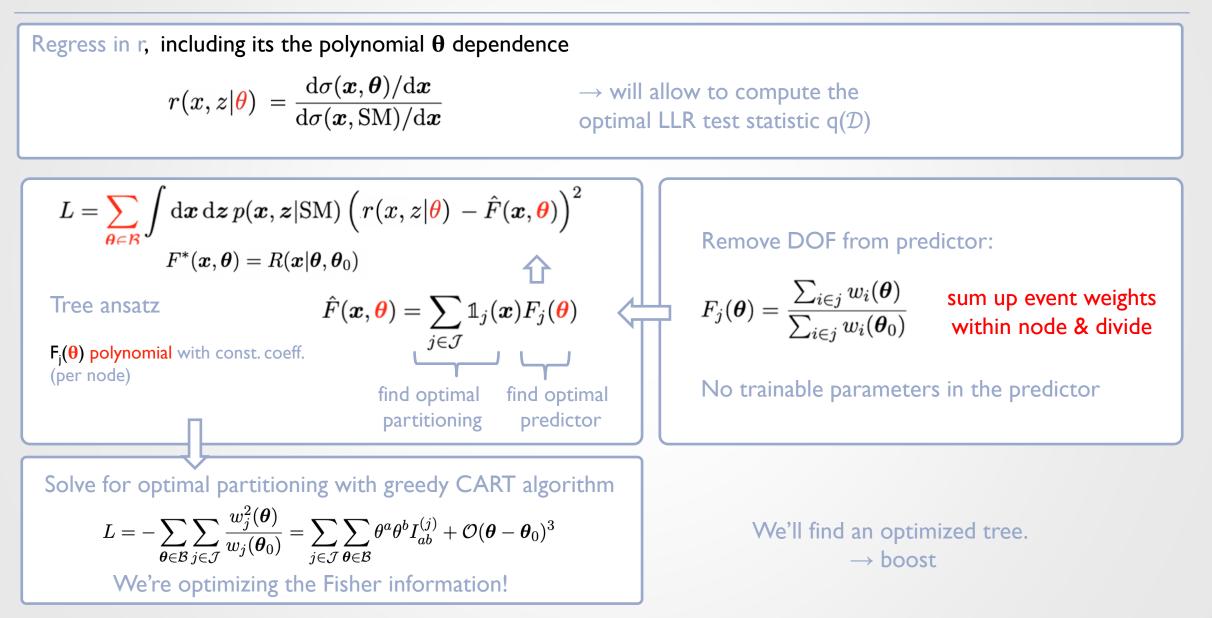


A SIMPLE TREE ALGORITHM



- Let us make a tree-based ansatz for the differential cross-section ratio R
- The "weak learner" is a tree associating a sub-region (j) of a partitioning \mathcal{J} with a predictive function F_i
 - Note: A tree algorithm can have an arbitrarily complicated predictive function; here it is a SMEFT polynomial
 - Fitting tree: Optimize "node split positions" on some loss. Trained (e.g. greedily) on the ensemble.

PARAMETRIZED TREES



CONCRETE SOLUTION: TREE BOOSTING

- Boosting: Fit model iteratively to pseudo-residuals of the preceding iteration with learning rate η

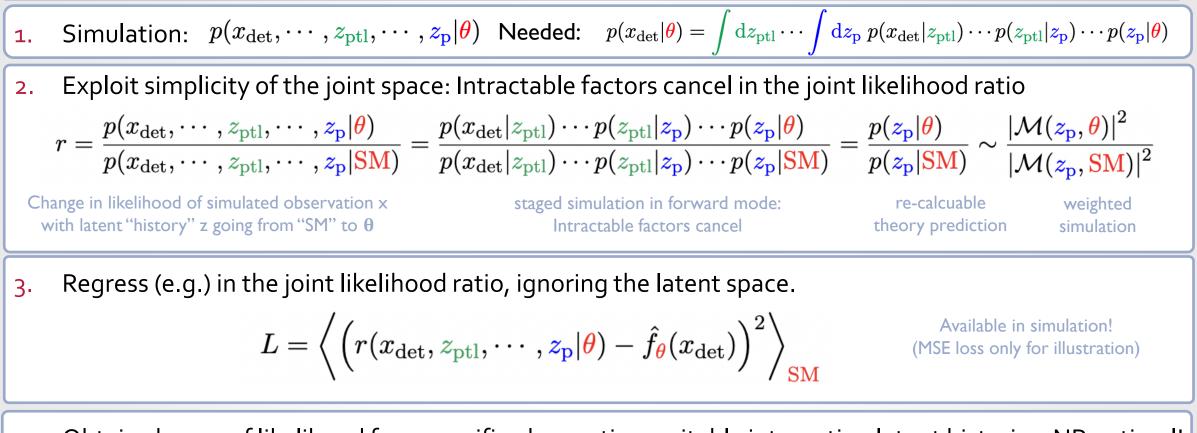
• Ansatz :
$$\hat{F}^{(b)}(\boldsymbol{x}, \boldsymbol{\theta}) = \hat{f}(\boldsymbol{x}, \boldsymbol{\theta}) + \eta \hat{F}^{(b-1)}(\boldsymbol{x}, \boldsymbol{\theta})$$

current previous iteration

• Insert into the loss function:

.... perform this iteratively "Boosted Information Tree"

SIMULATION BASED INFERENCE



4. Obtain change of likelihood for a specific observation, suitably integrating latent histories. NP optimal!

$$\operatorname{argmin}_{\hat{f}(x)} L = \frac{p(x|\theta)}{p(x|SM)} = \text{ ratio of integrals}$$

what we actually want: change in likelihood of a specific observation